

# Design and timing characterization of radiation-hard circuits for monolithic sensors

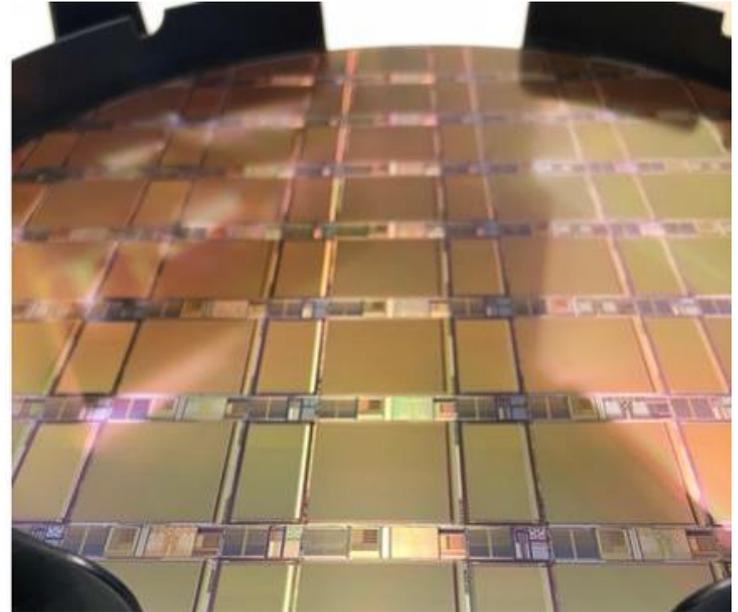
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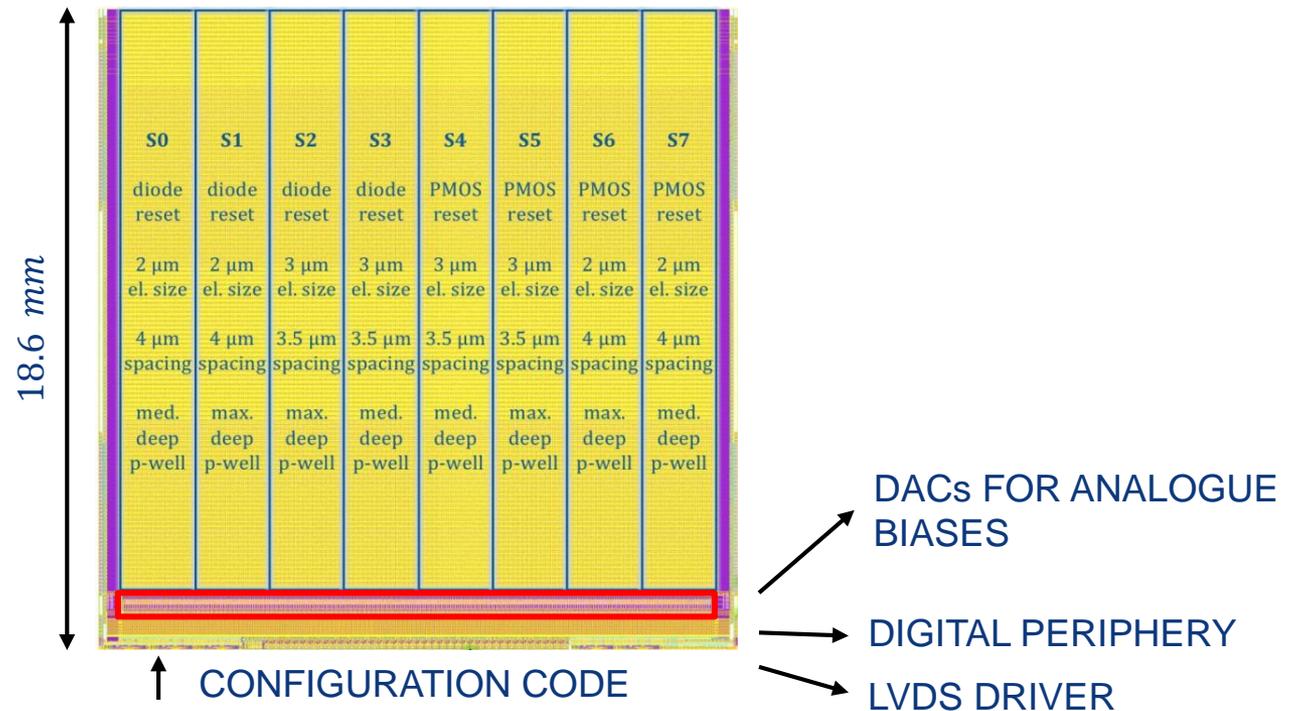


# OUTLINE

- **DACs and biasing circuits**
  - Concepts
  - Voltage & Current DAC design
  - Measurements
- **Low power Front-End design**
  - Front-End circuit design
  - Simulation results
  - In-pixel tuning DAC
- **Timing characterization of MALTA**
  - MALTA asynchronous output
  - PicoTDC specifications
  - Lab measurements
  - Testbeam
- **Conclusions**



# DACs and biasing circuits



In a pixel sensor, part of the chip is dedicated to the DACs: blocks to bias the circuits providing a current or a voltage configurable through a digital code.

Challenges:

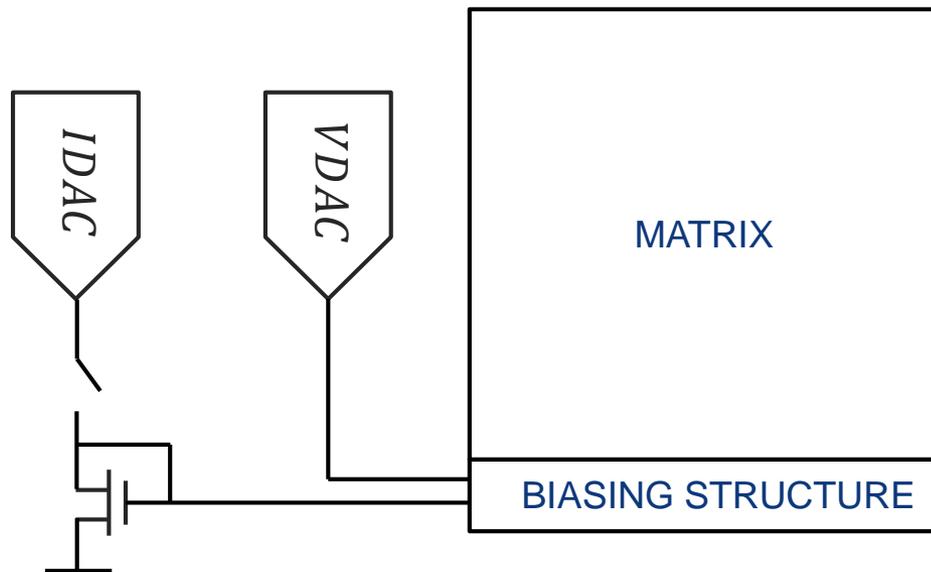
Independent from process, voltage and temperature.

Linear behavior as a function of code.

Small area.



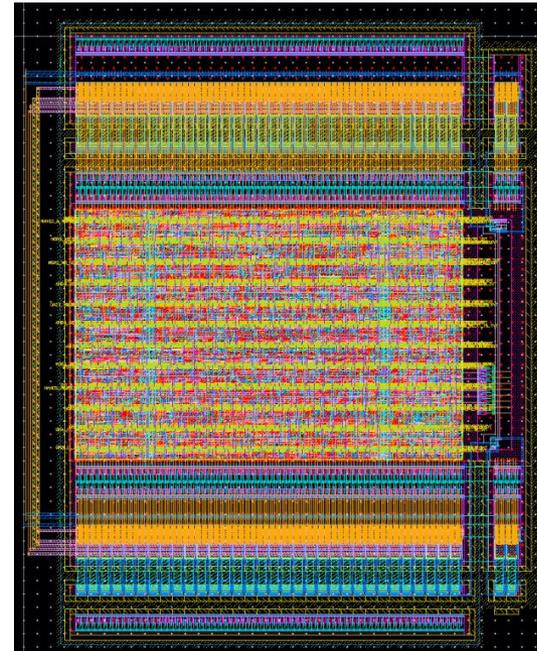
# MiniMALTA DACs concept



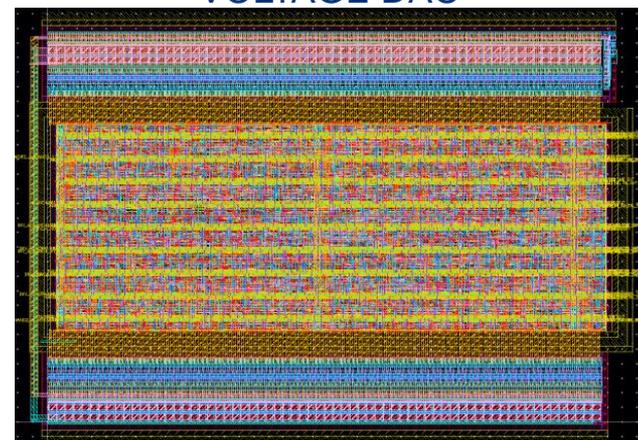
Non Modular design:

- Local DACs implemented to save space ( $\sim 5x$  with respect to a modular approach)
- Number of bits independent from the Matrix width (8 bits DACs implemented)
- Easy to increase the number of DACs and biasing lines towards the FE
- Flexible layout

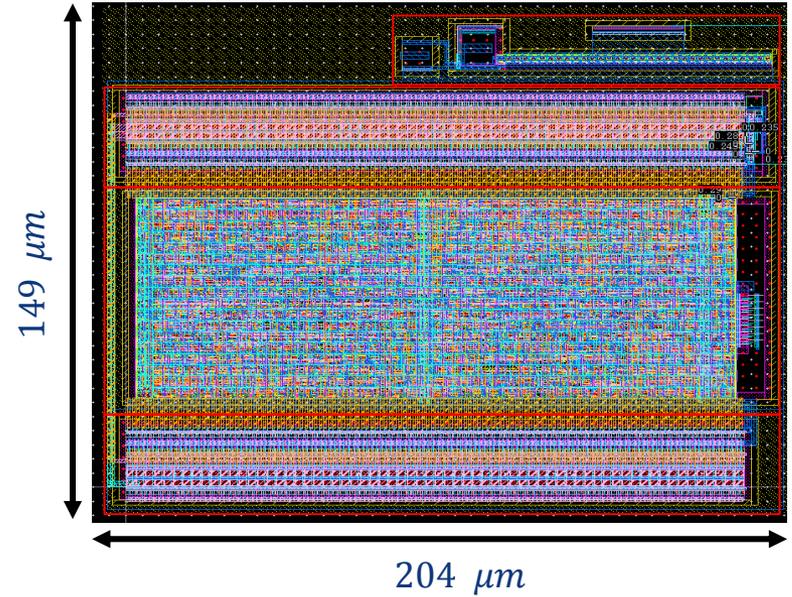
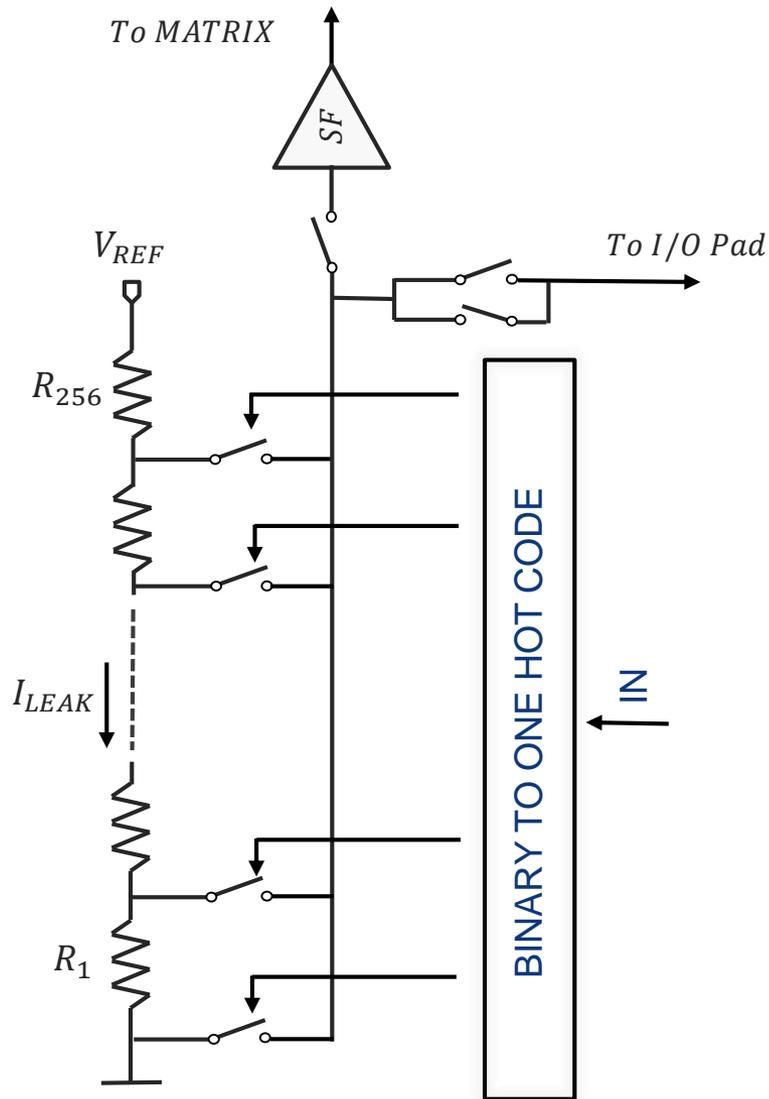
CURRENT DAC



VOLTAGE DAC

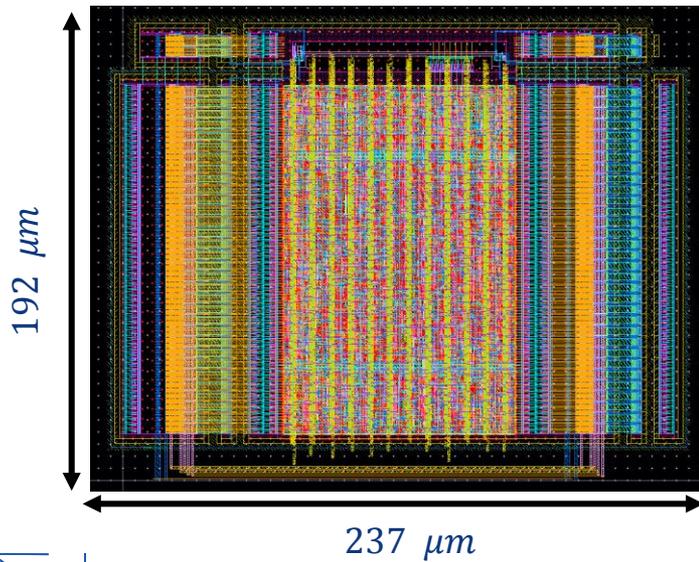
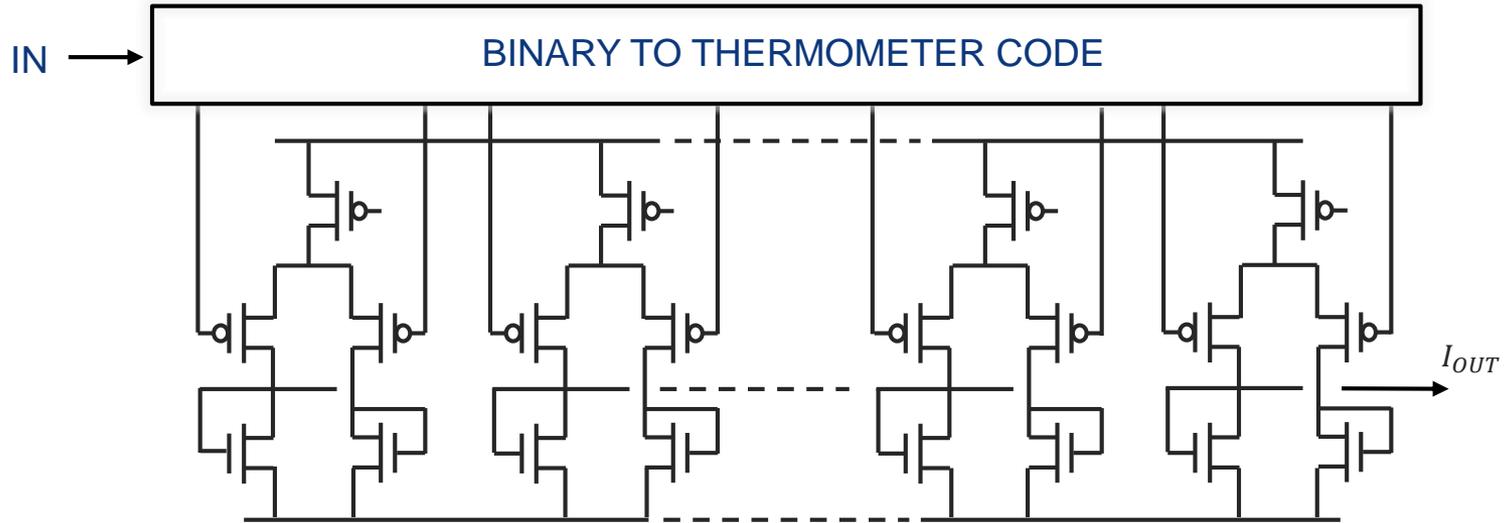


# Voltage DAC



TYPE	RESISTOR STRING
RESOLUTION	8 BITS (LSB=7.03mV)
POWER	32 $\mu\text{W}$
AREA	204 x 149 $\mu\text{m}^2$

# Current DAC

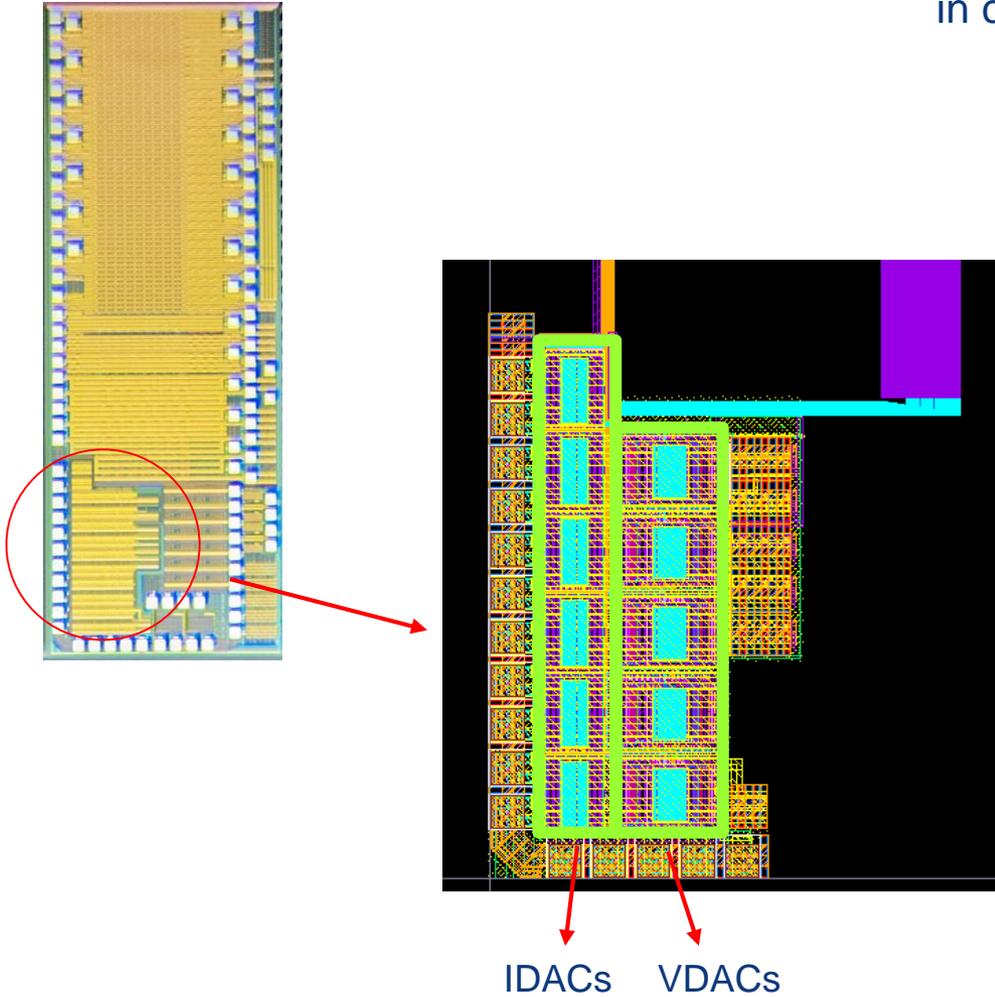


Possibility to override and monitor the current.

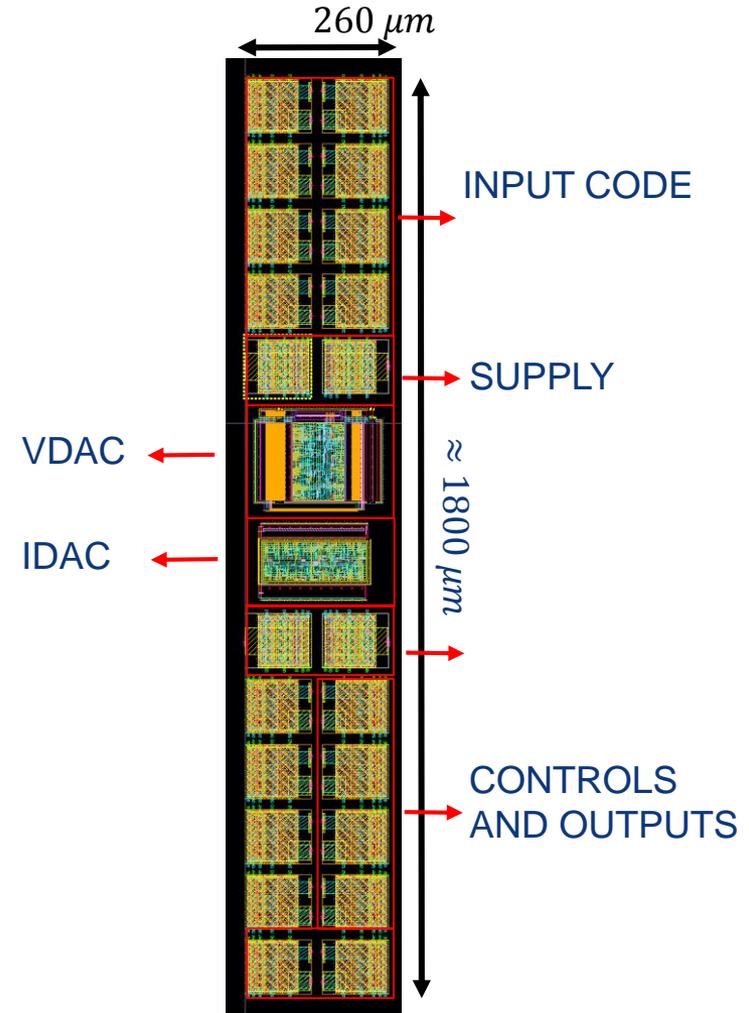
TYPE	PMOS CURRENT SOURCE
RESOLUTION	8 BITS ( $LSB \approx 20nA$ )
POWER	$14 \mu W$
AREA	$192 \times 237 \mu m^2$

# Integration in MiniMALTA and testchip

MiniMalta



Test-chip implemented as a baseline solution in case of malfunctioning on MiniMALTA

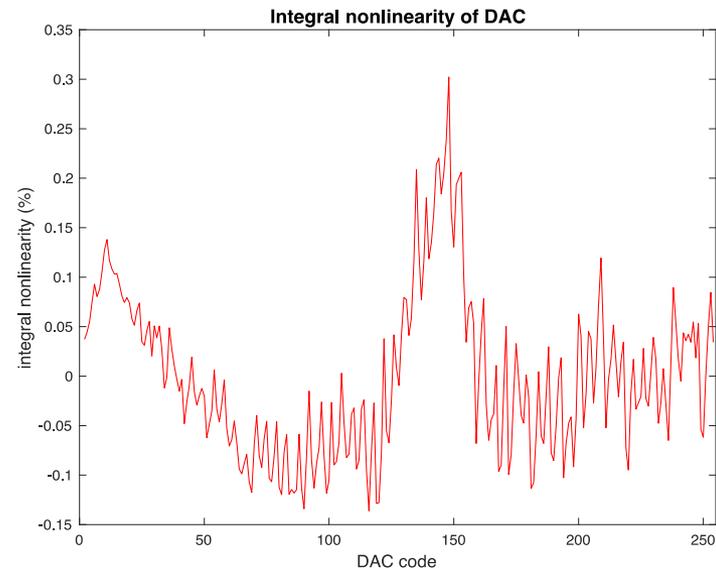
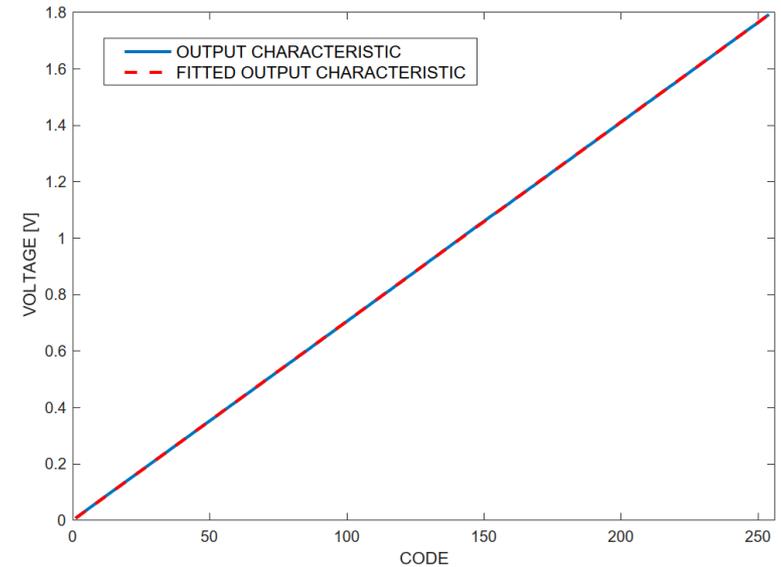
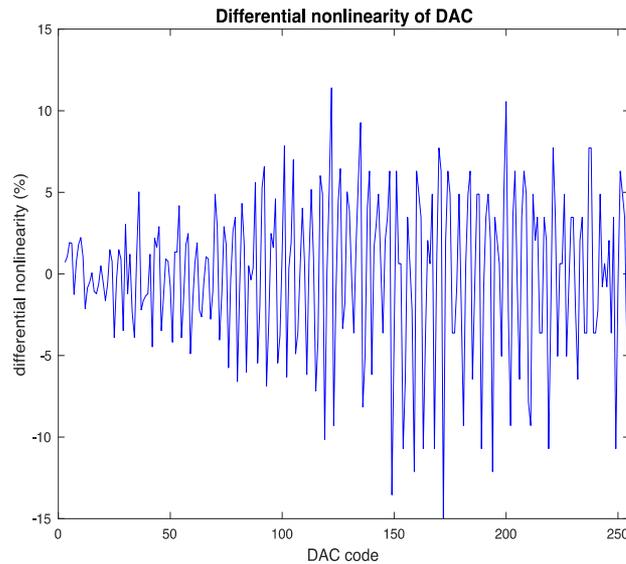


# Linearity of the VDACs vs TID

Measurement on 15 chips before and after ionizing radiation (TID).

	DNL	INL
NO_IRR	12%	40%
1MRad	18%	42%
66MRad	16%	35%
91MRad	15%	30%

91 MRad:

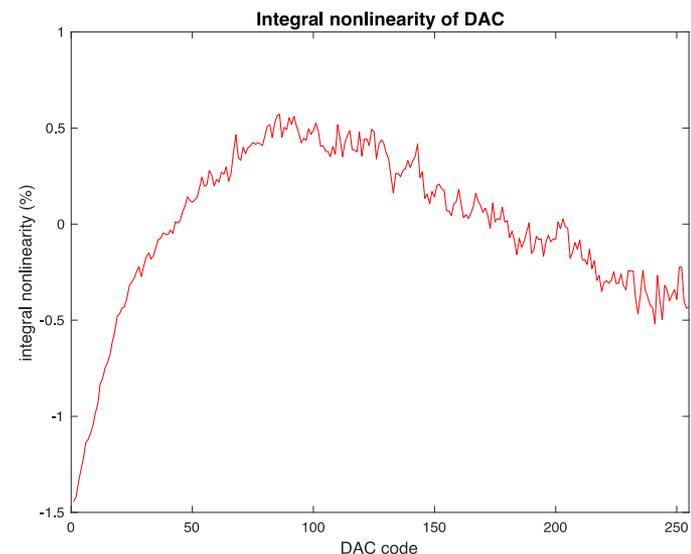
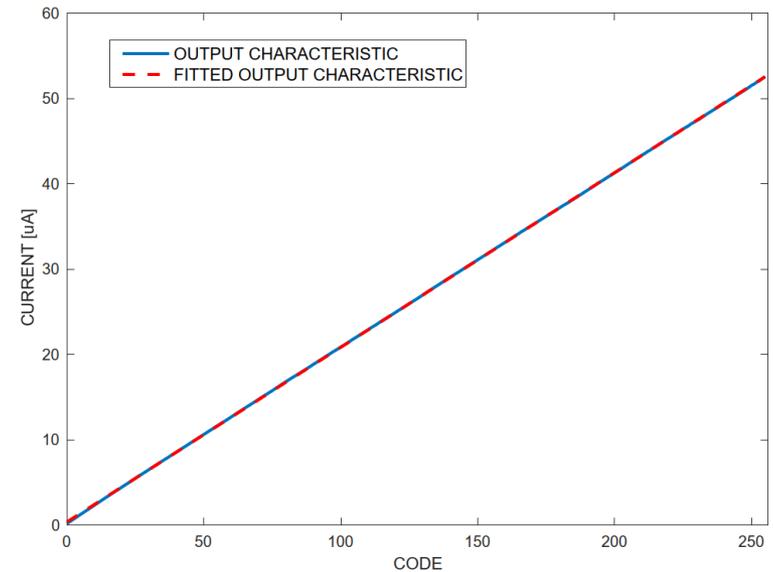
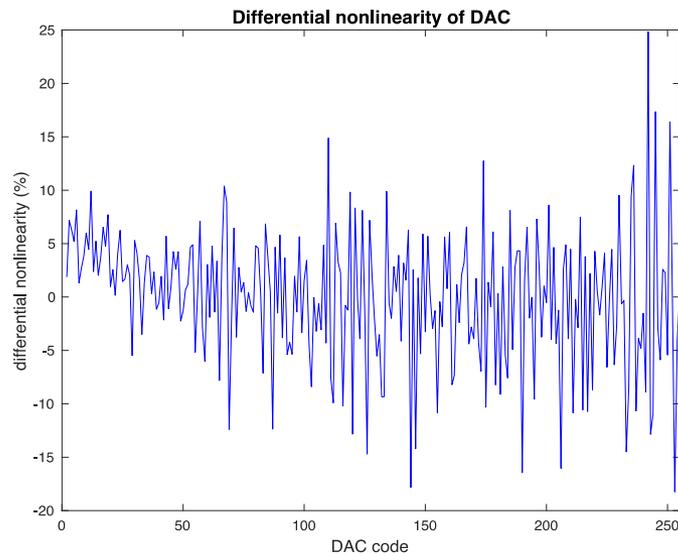


# Linearity of the IDACs vs TID

Measurement on 15 chips before and after ionizing radiation (TID).

	DNL	INL
NO_IRR	18%	40%
1MRad	30%	130%
66MRad	29%	111%
91MRad	25%	140%

91 MRad:



# IDACs testing - mismatch

Measurement on 15 chips before and after ionizing radiation (TID).

SAMPLE	ITHR	IRESET	IDB	ICASN	IBIAS	AVG per sample
#1	57.6	56.6	57.9	56.4	58.3	57.36
#2	54.2	55.2	54.2	54.9	54.9	54.68
#3	59.9	59.9	59.5	59.6	59.3	59.64
#4	59.4	58.8	59.2	59.1	59.4	59.18
AVG per channel T=27C	57.775	57.625	57.7	57.5	57.975	57.595
T=-30C	52.7325	52.365	52.565	52.25	52.85	52.5525
After irradiation	51.092	51.80	51.200	51.3287	51.82	51.448

Current ranges are dependent on process, temperature and also ionizing radiation dose.

Similar values of average currents for the different channels indicate no design issue.

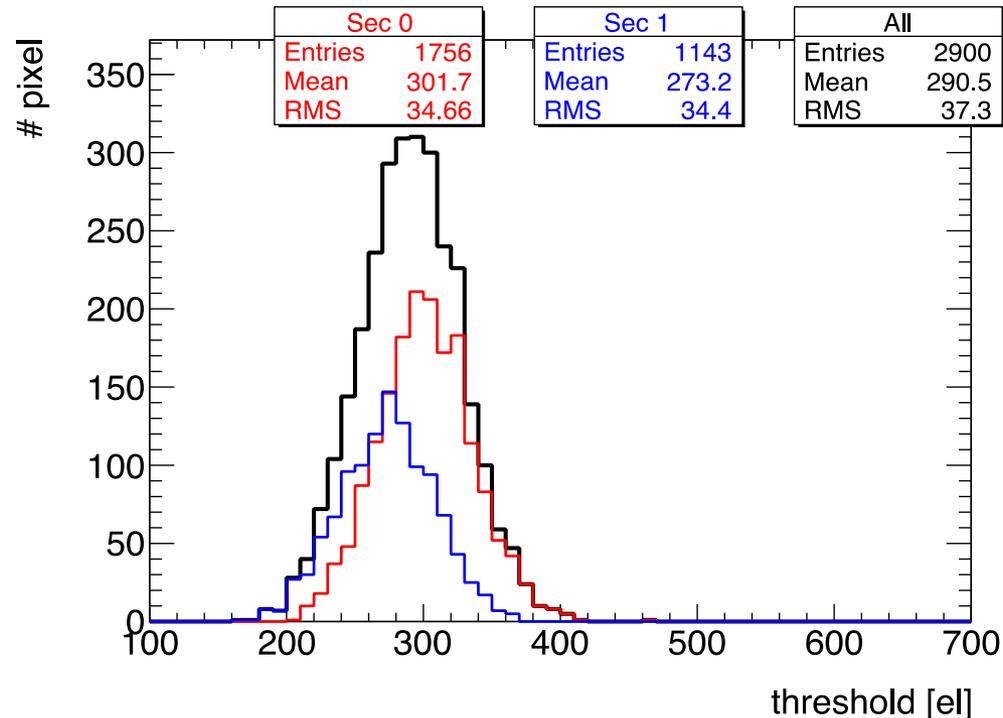
→ Possibility to use it with a Bandgap reference for a better PVT independence.

# DACs and biasing circuits

The DACs are setting global references to the pixel matrix but there is a pixel to pixel variability due to the lithographic process.

Noise and transistor mismatch cause a variation on important Front-End characteristics as gain, threshold etc.

The behavior over the chip has to be as uniform as possible.



# Front-End threshold dispersion

FE study to improve overall performance, focusing on threshold dispersion.

Main source of Mismatch are:

- the discriminator input transistor M11

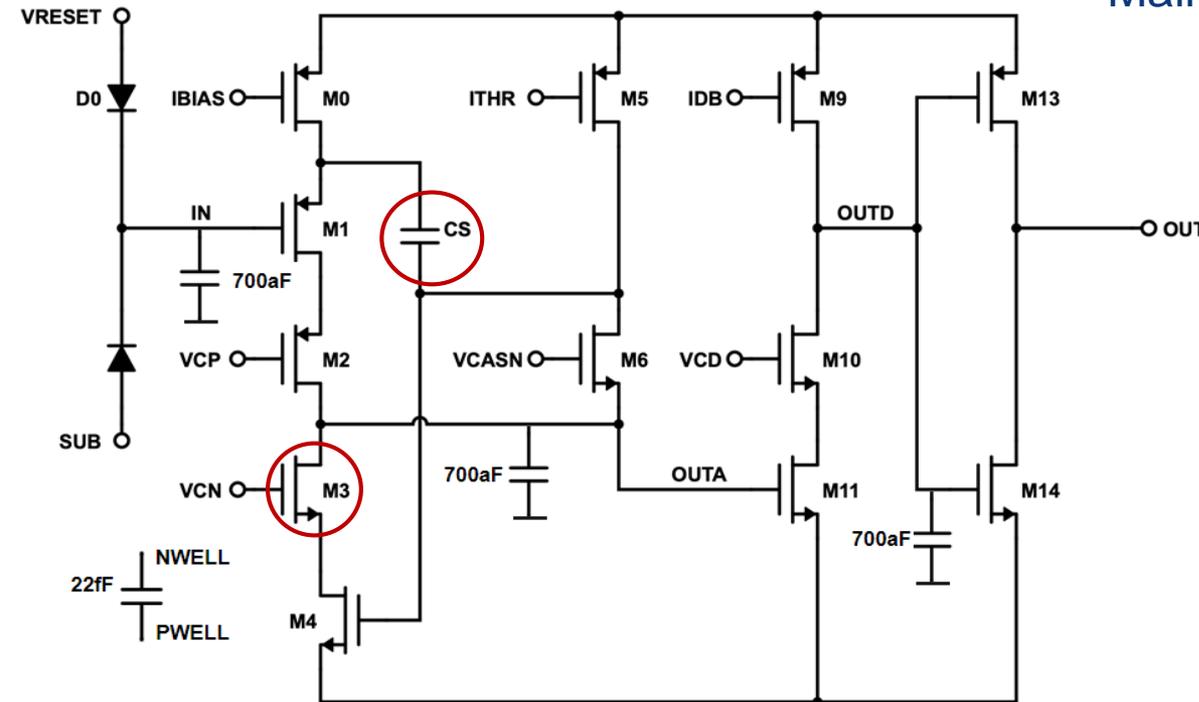
$$\sqrt{\left(\sigma_{IN} \cdot \frac{dA_Q}{dQ}\right)^2 + \sigma_1^2 + \sigma_{VTH}^2 \cdot g_m} = \sigma_I$$

- the output conductance of the sink transistor



Added M3 to cascode sink transistor M4

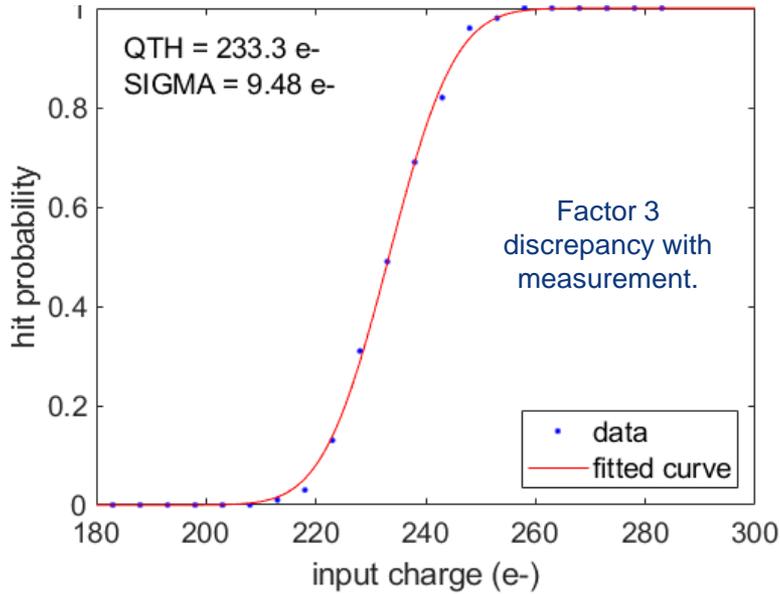
Relevant RTS contributor, transistor M4: enlarged for next developments



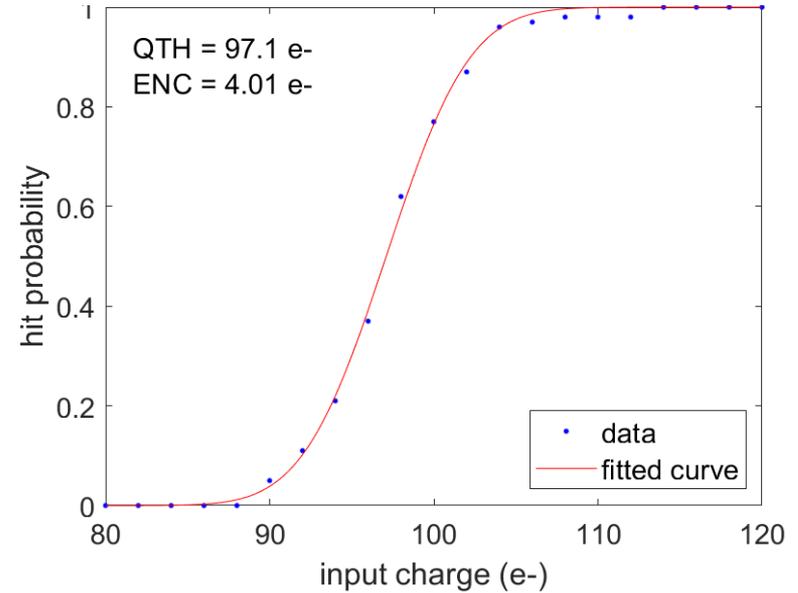
Larger (4x) filtering capacitance from previous version: further improvement on the gain and better stability

# Front-End threshold dispersion - simulation

w/o cascade (MALTA/MiniMALTA)



w cascade, bigger cap



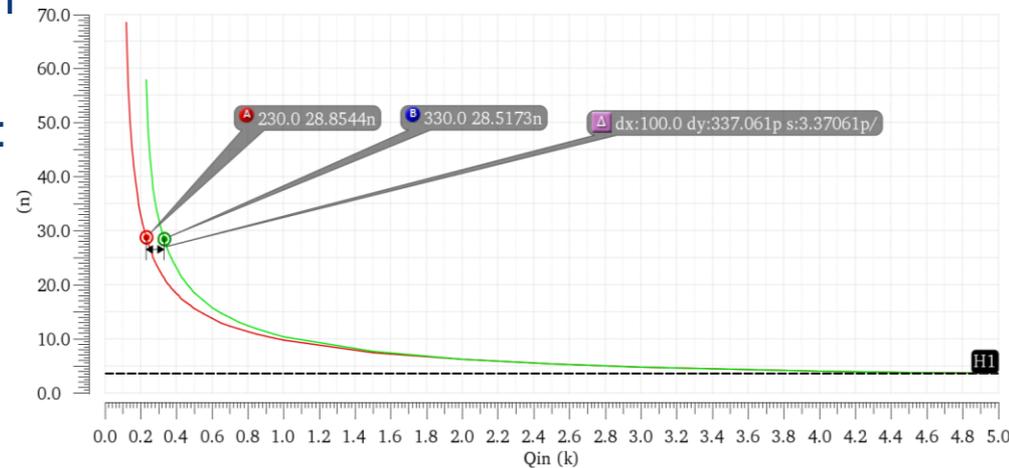
2x more signal for the same charge with cascade.

Faster Front-End with the same charge:  
lower Time Walk and in time threshold.

Potentially better efficiency.

Better time resolution.

TIME WALK curve



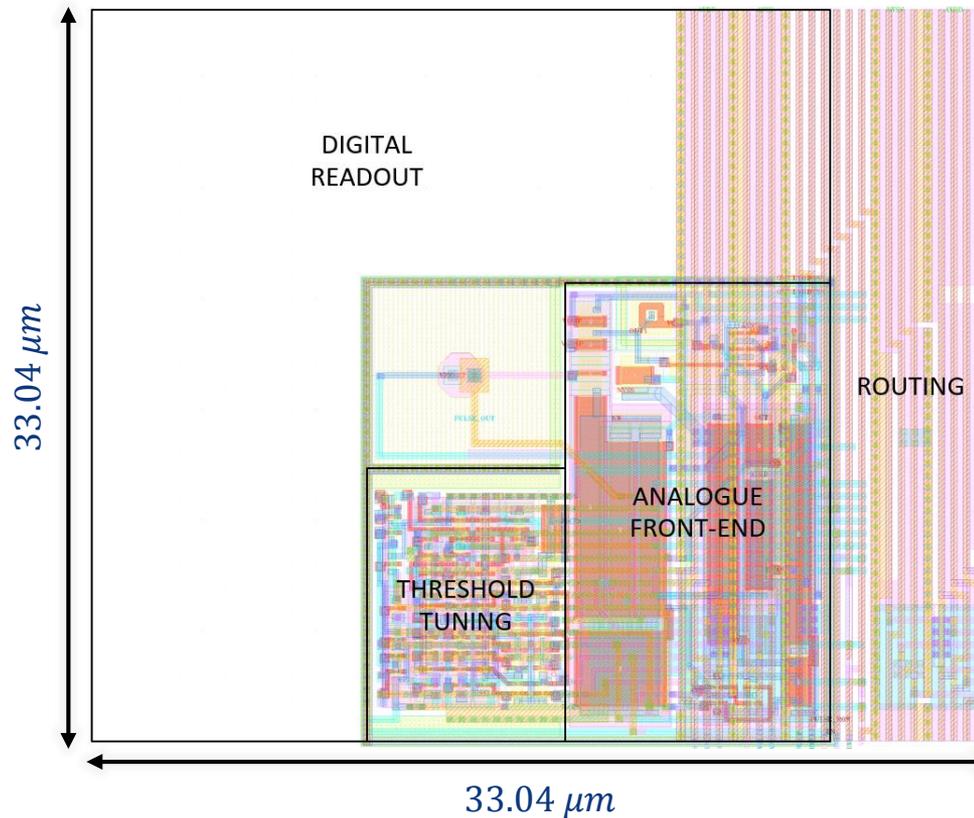
# Pixel design

To further reduce the dispersion a local adjustment is implemented.



A three bit DAC has been integrated “in pixel”.

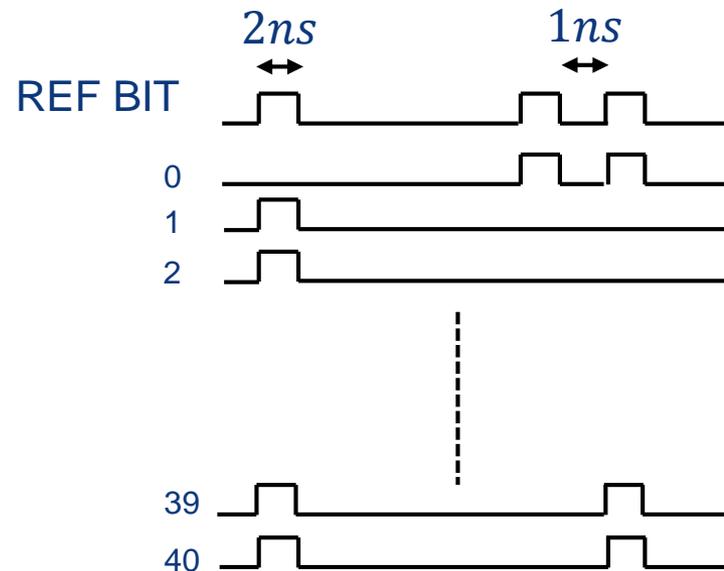
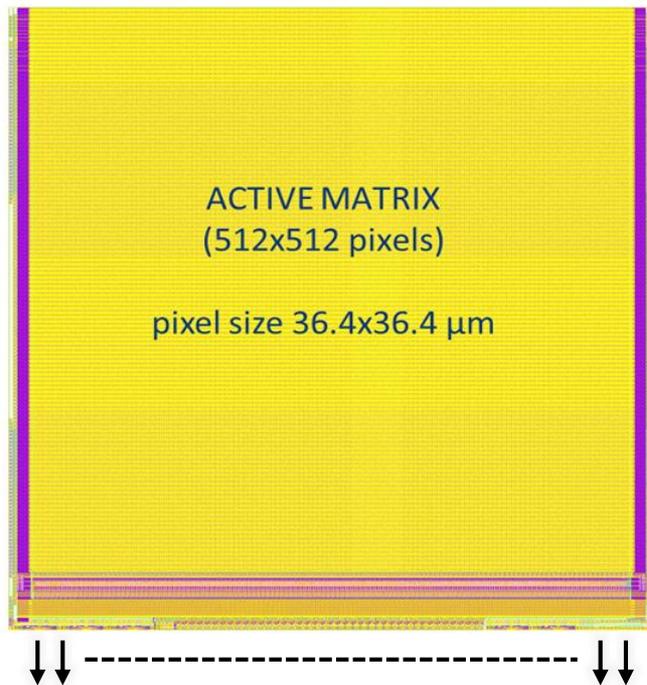
Reduction by a x7 factor the threshold dispersion.



# Timing measurements MALTA+PicoTDC

Malta gives output data asynchronously on a 40 bits bus to provide information on hit position on the matrix.

The outputs are LVDS-compatible (LAPA drivers, see Roberto's presentation).



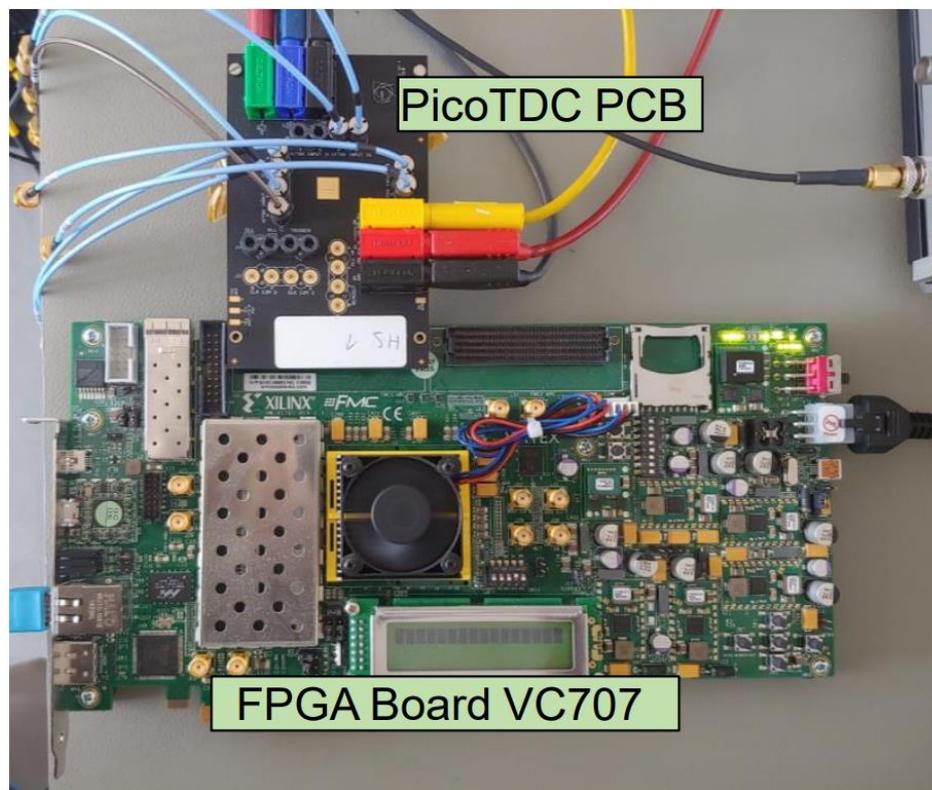
The REF bit is a fast OR signal, high whenever a hit has occurred on the matrix.

# PicoTDC features

The PicoTDC is a Time to Digital Converter with a 3 ps binning capability.

It has 64 LVDS input channels compatible with LAPA.

The data are stored in a FIFO and sent out serially through an 8 bit port.



# Lab setup

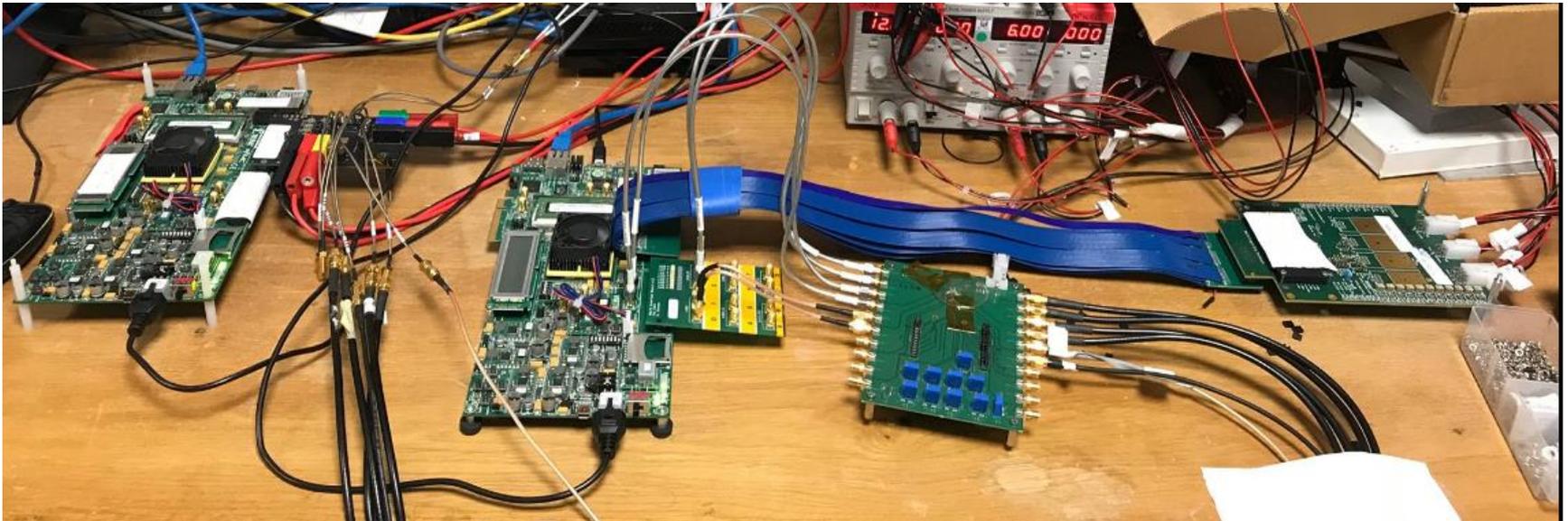
FPGA for PicoTDC

FPGA for MALTA

PicoTDC

LAPA board

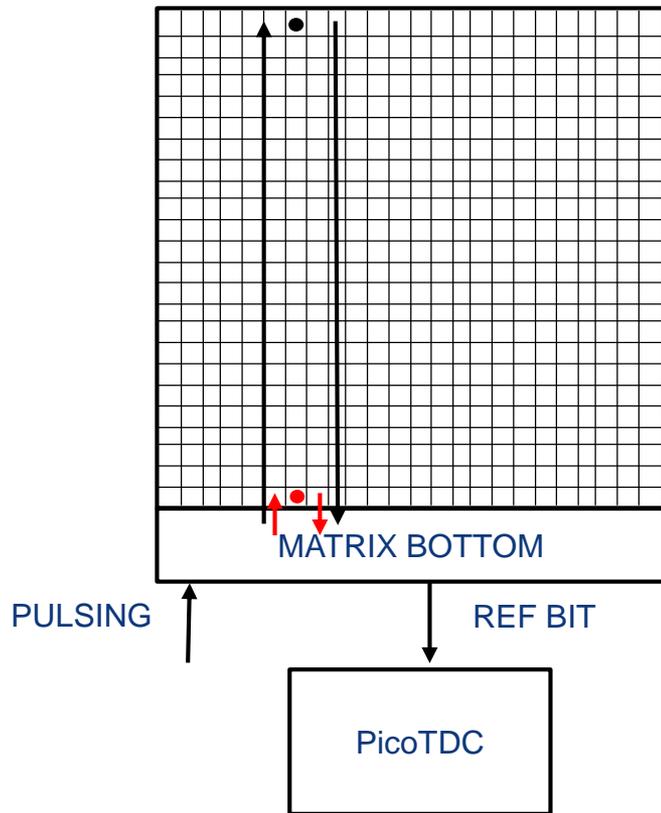
MALTA



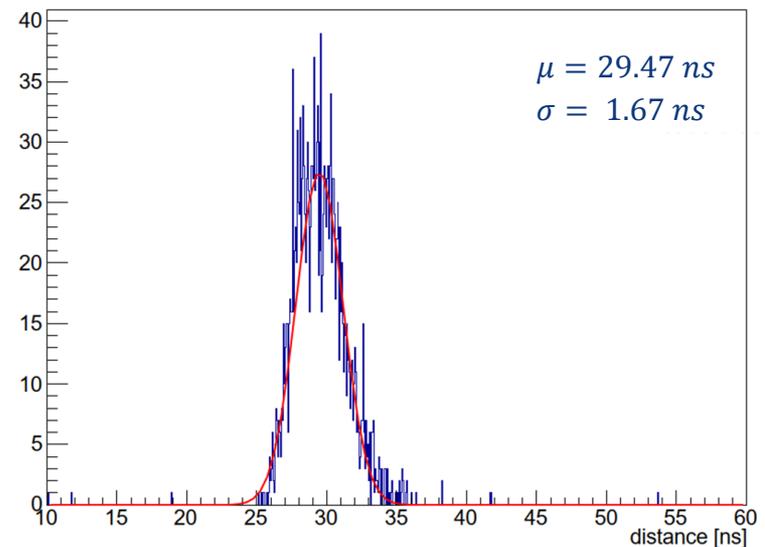
LAPA board needed to restore signals levels to MALTA

# Timing characterization of MALTA

Time of arrival characterization of the REF signal with test pulses.  
Pulsed two pixels in the same column.



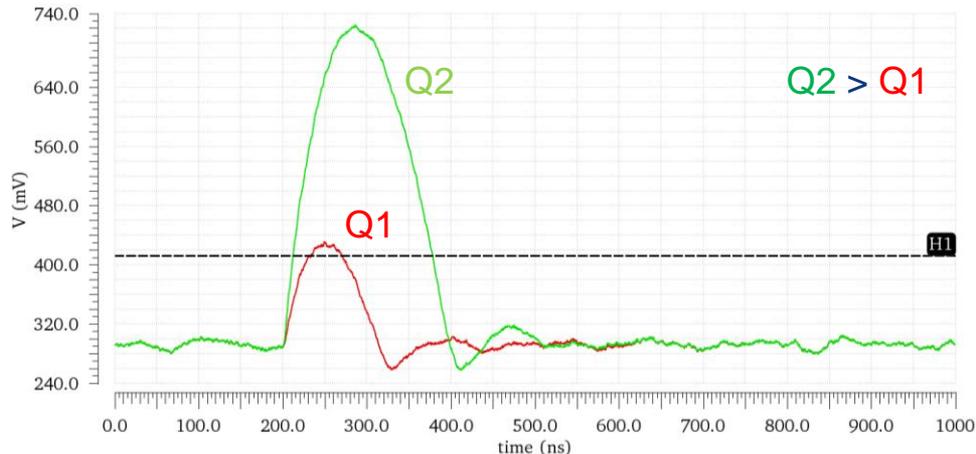
Distribution of REF time of arrival difference



Sigma of the distribution is the Front-End and read out circuitry jitter

# Front-End time resolution

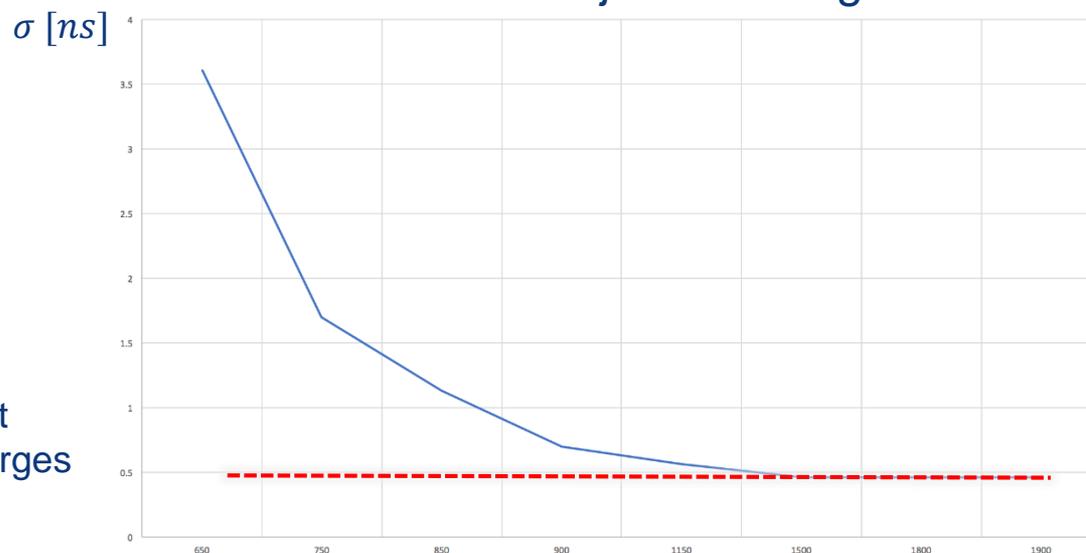
The level of noise and signal speed affect the time resolution



Time jitter

$$\sigma_t = \sigma_{vn} \setminus \frac{dV}{dT}$$

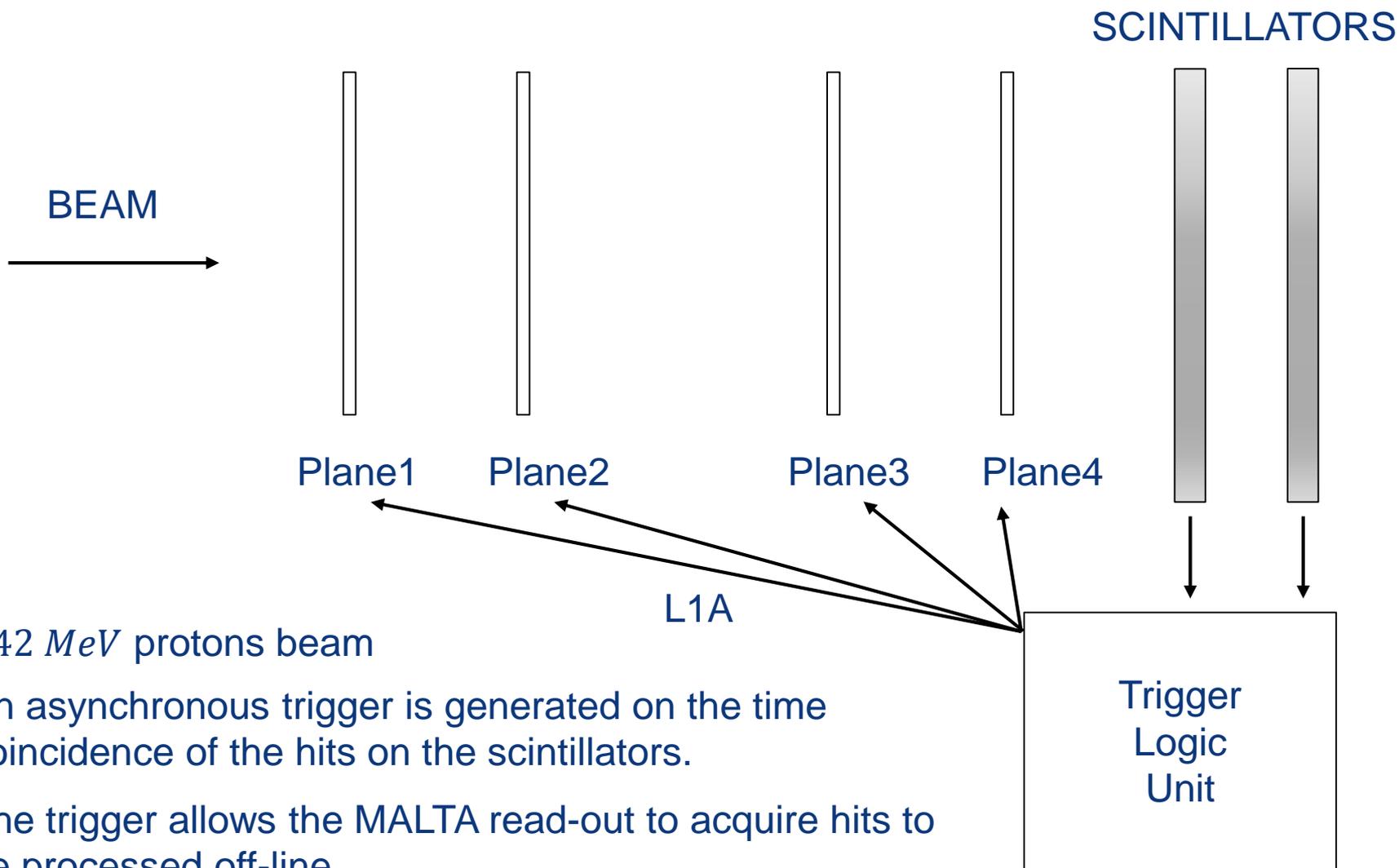
### Jitter vs injected charge



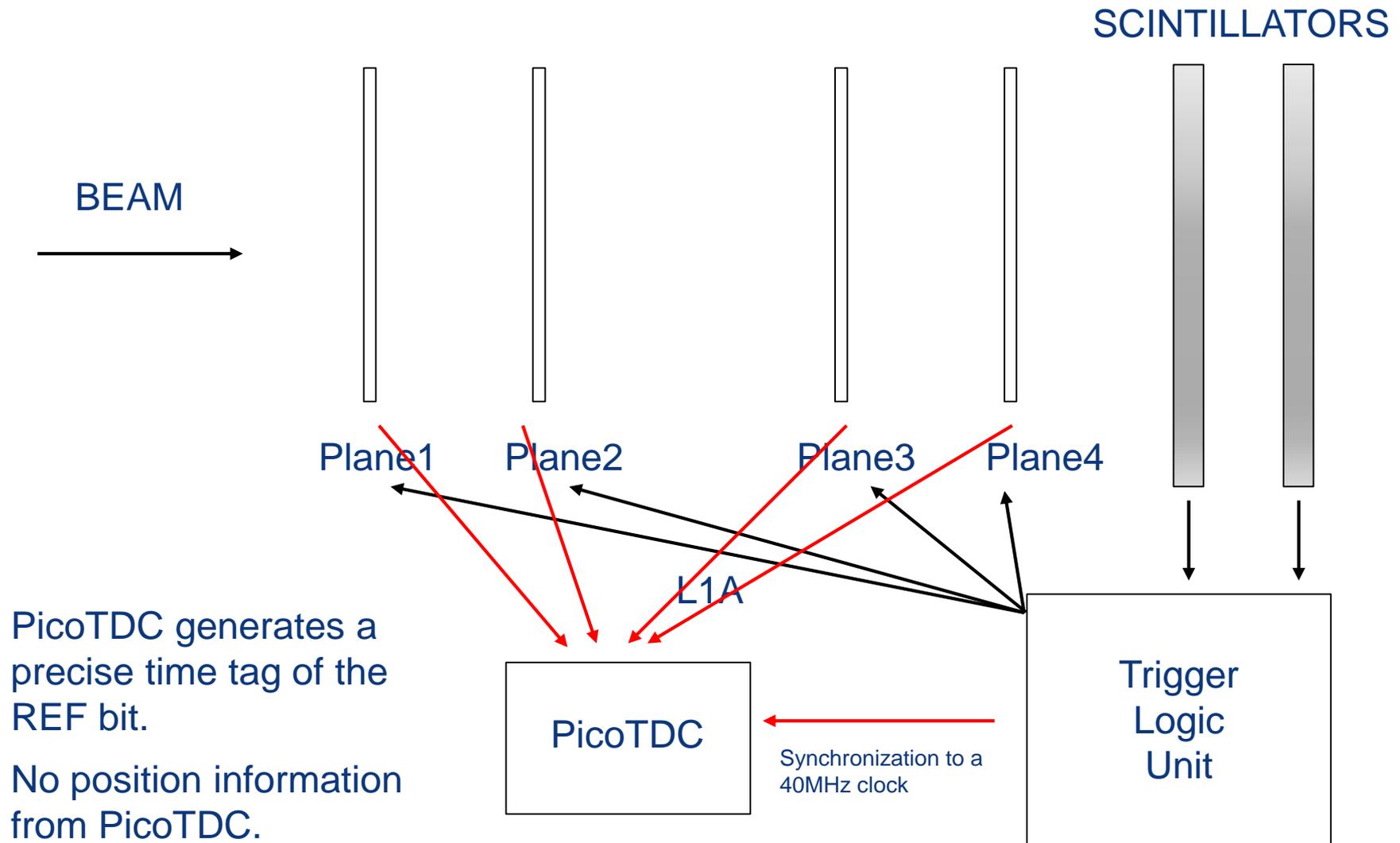
Flattens out at 500ps for charges > 1.5ke

$Q_{IN} [e^-]$

# Test beam - setup

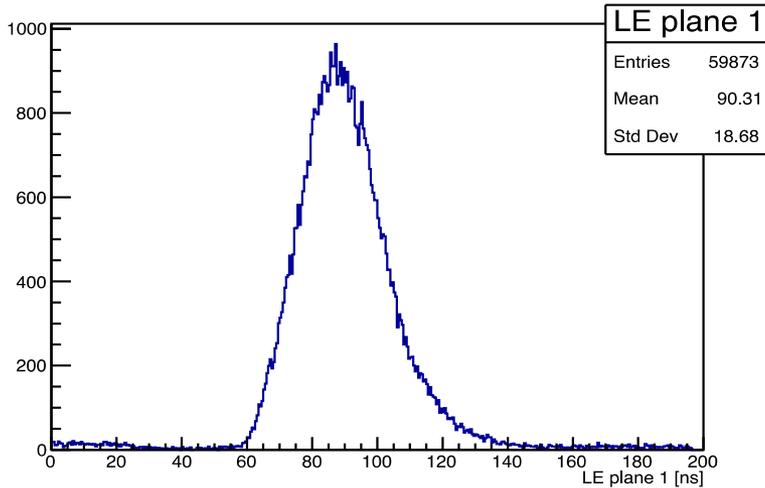


# PicoTDC – integration in setup



# TestBeam - results

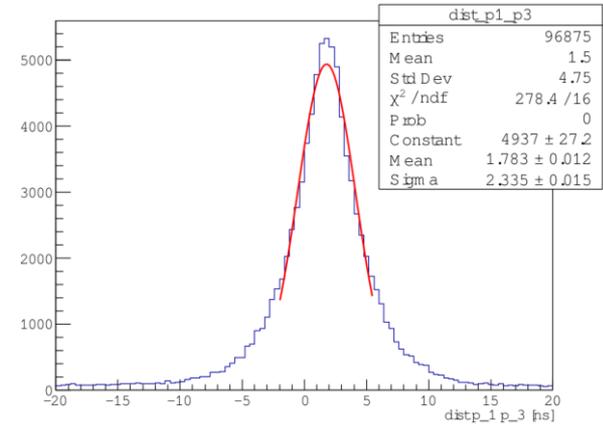
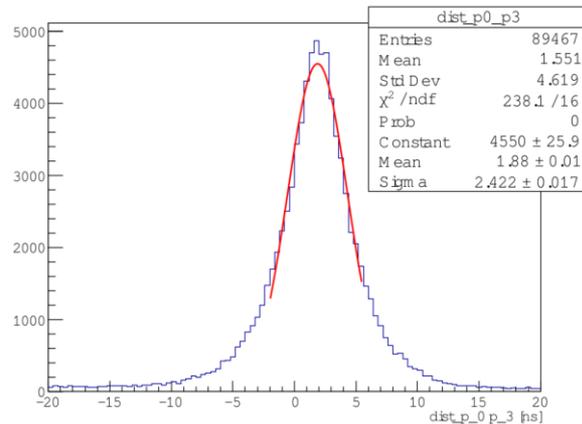
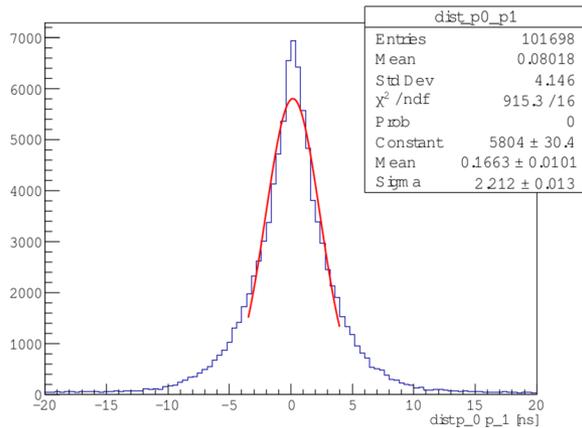
Distribution of the REF bits with respect to the trigger.



Two contribution to the sigma:

- MALTA jitter
- Jitter due to the trigger synchronization with a 40 MHz clock (dominant).

Timing difference between planes (first of the cluster in case of multiple hits).

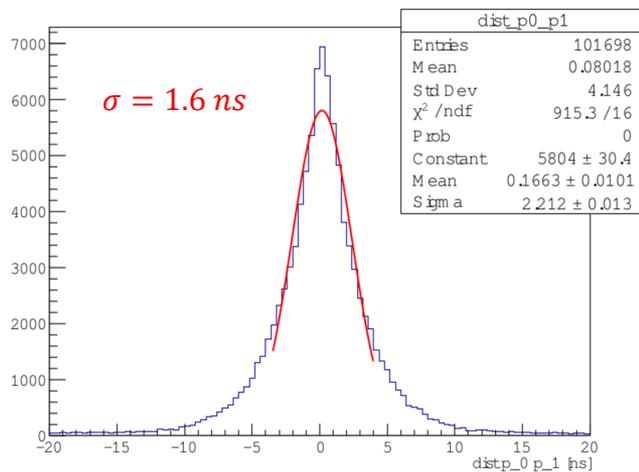


Assuming the different planes uncorrelated:  $\sigma_t = 1.6 \text{ ns}$

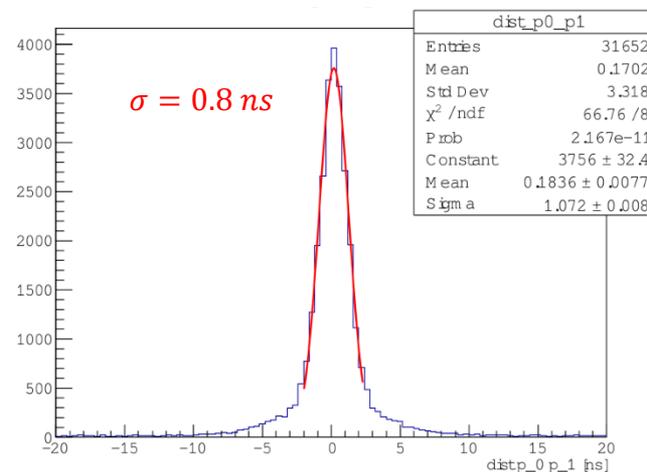
# TestBeam - results

Protons beam at 142 MeV  $\rightarrow \approx x3$  MIP

The resolution is improved considering only higher charges (single pixel cluster)



After cutting on  
multiple hits clusters



No information on hit position:

Gaussian tails due to noisy hits

Shifted average due to column propagation

Future measurements will include correlation between PicoTDC and Malta.

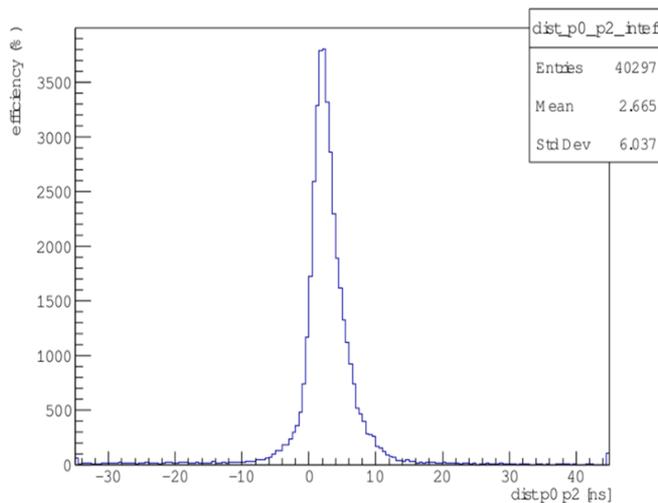
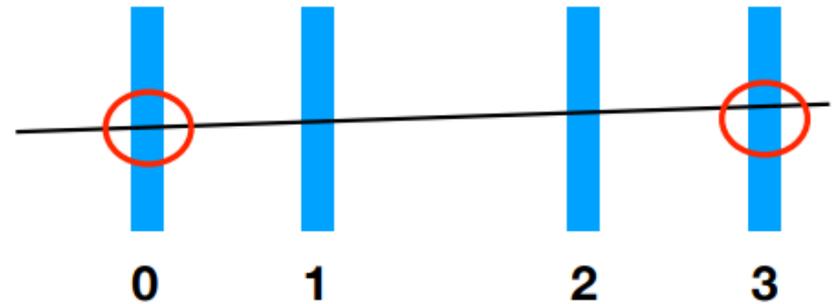
# In-time efficiency with PicoTDC

Important information can be extracted from PicoTDC analysis.

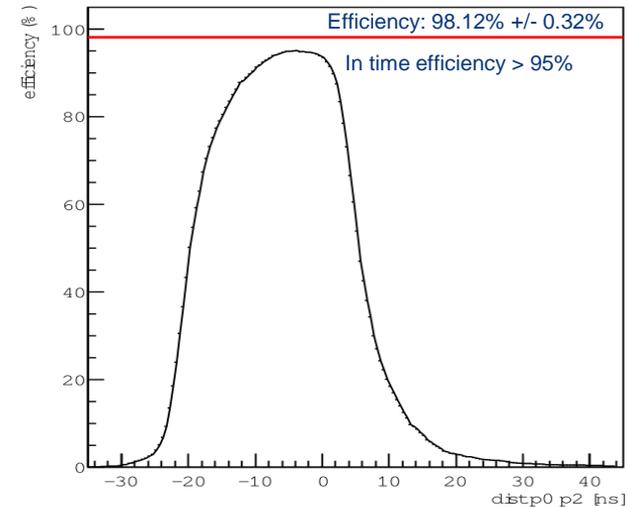
How to define a track:

Require one hit on the first (origin) and last plane

Efficiency = fraction of tracks seen on other planes



Integration on a moving window of 25ns



Efficiency compatible with other analysis (see Roberto's presentation)

Next step: correlation with position information to cut noisy hits.

# Conclusions

Designed biasing circuits for monolithic pixel sensors (MiniMALTA, MONOPIX)

extensively characterized with lab measurements and show good results in terms of linearity and radiation hardness

An thorough study on the Front-End has been carried out and a factor 2 improvement in threshold dispersion has been achieved in simulations

The Front-End modification have been implemented in a new layout including a in-pixel tuning DAC and will be used for future TowerJazz developments.

A testing system for MALTA timing characterization which includes a fast timing ASIC (PicoTDC) has been implemented.

A sub ns time resolution has been achieved with lab measurements and a 1.8ns resolution with testbeams.